

## Freeform Search

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<b>Database:</b>	US Pre-Grant Publication Full-Text Database
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	EPO Abstracts Database
	JPO Abstracts Database
	Derwent World Patents Index
	IBM Technical Disclosure Bulletins

<b>Term:</b>	L17 and (shutting off)
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<b>Display:</b>	<input type="text" value="50"/> Documents in Display Format: <input type="text" value="-"/>	Starting with Number <input type="text" value="1"/>
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<b>Generate:</b>	<input type="radio"/> Hit List	<input checked="" type="radio"/> Hit Count	<input type="radio"/> Side by Side	<input type="radio"/> Image
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Search	Clear	Interrupt
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### Search History

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DATE: Monday, April 12, 2004   [Printable Copy](#)   [Create Case](#)

**Set Name Query**  
side by side

**Hit Count Set Name**  
result set

*DB=PGPB,USPT; PLUR=YES; OP=ADJ*

<u>L18</u>	L17 and (shutting off)	1	<u>L18</u>
<u>L17</u>	09/819612	1	<u>L17</u>
<u>L16</u>	L15 and @ad<20000101	22	<u>L16</u>
<u>L15</u>	L8 and backup	64	<u>L15</u>
<u>L14</u>	L13 and @ad<20010301	11	<u>L14</u>
<u>L13</u>	L8 and (backup near3 server)	18	<u>L13</u>
<u>L12</u>	L11 and 345/\$.ccls.	5	<u>L12</u>
<u>L11</u>	L9 and 705/\$.ccls.	158	<u>L11</u>
<u>L10</u>	L9 and 707/\$.ccls.	36	<u>L10</u>
<u>L9</u>	virtual store	311	<u>L9</u>
<u>L8</u>	production management	933	<u>L8</u>
<u>L7</u>	L6 and server	18	<u>L7</u>
<u>L6</u>	L5 and @ad<20010301	22	<u>L6</u>
<u>L5</u>	L4 and (replicat\$3 near3 trigger)	25	<u>L5</u>
<u>L4</u>	L3 and backup	32910	<u>L4</u>
<u>L3</u>	product\$3 or manufactur\$3	2377465	<u>L3</u>

<u>L2</u>	L1 and product\$3	0	<u>L2</u>
<u>L1</u>	5758067.pn. or 6367029.pn.	2	<u>L1</u>

END OF SEARCH HISTORY



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## Search Results

Search Results for: **[replication trigger]**


Found **1** of **130,565** searched.

## Search within Results




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Sort by: **Title** **Publication** **Publication Date** **Score**  **Binder**

**Results 1 - 1 of 1** **short listing**

- 1** Update propagation strategies to improve freshness in lazy master replicated databases 77%  
 Esther Pacitti , Eric Simon  
**The VLDB Journal — The International Journal on Very Large Data Bases** February 2000  
 Volume 8 Issue 3-4  
 Many distributed database applications need to replicate data to improve data availability and query response time. The two-phase commit protocol guarantees mutual consistency of replicated data but does not provide good performance. Lazy replication has been used as an alternative solution in several types of applications such as on-line financial transactions and telecommunication systems. In this case, mutual consistency is relaxed and the concept of freshness is used to measure the deviation ...

**Results 1 - 1 of 1** **short listing**

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You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard**Results:****No documents matched your query.**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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